

<b>INFORMATION DISCLOSURE CITATION</b> <i>(Use several sheets if necessary)</i>				Docket Number (Optional) <b>WFS.006 CIP</b>		Application Number <b>NEW 10/828,550</b>		
				Applicant(s) <b>Daniel R. NEAL et al.</b>				
				Filing Date <b>21 April 2004</b>		Group Art Unit <b>TBD 2873</b>		
<b>U.S. PATENT DOCUMENTS</b>								
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
/JS/	A	6,199,986	03/13/2001	Williams et al.				
	B	6,299,311 B1	10/09/2001	Williams et al.				
	C	4,725,138	02/16/1988	Wirth et al.				
	D	5,978,053	11/02/1999	Giles et al.				
	E	6,095,651	11/01/2000	Williams et al.				
	F	6,270,221 B1	08/07/2001	Liang et al.				
	G	5,258,791	11/02/1993	Penney et al.				
	H	4,021,102	05/03/1977	Iizuka				
	I	3,819,256	06/25/1974	Bellows et al.				
	J	5,929,970	07/27/1999	Mihashi				
/JS/	K	6,271,915 B1	08/07/2001	Frey et al.				
<b>FOREIGN PATENT DOCUMENTS</b>								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
/JS/	L	0 625 332 A2	11/23/1994	European Patent Office			✓	
	M	DE 42 22 395 A1	01/13/1994	Germany				✓
	N	0 373 788 A2	06/20/1990	European Patent Office			✓	
	O	WO 83/02716	08/18/1983	PCT				✓
/JS/	P	WO 01/89372 A2	11/29/2001	PCT			✓	
<b>OTHER DOCUMENTS</b> <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>								
/JS/	Q	Geary, Joseph M., Introduction to Wavefront Sensors, SPIE Press, Vol. TT18, copyright 1995, pages 93-95.						
EXAMINER <b>/Jessica Stultz/</b>				DATE CONSIDERED <b>09/28/2007</b>				
<b>EXAMINER:</b> Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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Applicant(s) <b>Daniel R. NEAL, et al.</b>	
Filing Date <b>21 April 2004</b>	Group Art Unit <b>TBD2873</b>

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/JS/	R	6,271,914 B1	08/07/2001	Frey et al.			

**FOREIGN PATENT DOCUMENTS**

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
/JS/	S	WO 01/78585	10/25/2001	PCT			✓	
/JS/	T	WO 01/82228 A2	11/01/2001	PCT			✓	

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

/JS/	U	International Search Report printed November 26, 2001, pages 1 and 2.

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10/828,550

Applicant(s)

Daniel R. Neal et al.

Filing Date

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Group Art Unit

TRD

2873

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/JS/	A	US-6,394,605 B1	5/28/2002	Campin et al.			
	B	US-6,382,795 B1	5/7/2002	Lai, Ming			
	C	US-6,130,419	10/10/2000	Neal, Daniel R.			
	D	US-6,052,180	4/18/2000	Neal et al.			
	E	US-5,936,720	8/10/1999	Neal et al.			
	F	US-5,493,391	2/20/1996	Neal et al.			
/JS/	G	US 5,617,157 A	04/1997	Shalon et al.			

**FOREIGN PATENT DOCUMENTS**

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
/JS/	C	WO 01/28408 A2	4/26/2001	PCT				

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

/JS/	H	Brown, et al.; Measurement of the dynamic deformation of a high frequency scanning mirror using a Shack-Hartmann wavefront sensor; SPIE's 46th Annual Meeting International Symposium on Optical Science and Technology 29 July - 3 August 2001; pages 1-9.
/JS/	I	Neal et al.; AIAA 98-2701 Shack-Hartmann wavefront sensor testing of aero-optic phenomena; 20th AIAA Advanced Measurement and Ground Testing Technology Conference June 15-18, 1998, pages 1-13.

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*EXAMINER INITIAL	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)
/JS/	J Daniel R. Neal et al.; Application of Shack-Hartmann Wavefront Sensors to Optical System Calibration and Alignment; pages 234-240.
	K Daniel R. Neal et al.; Characterization of Infrared Laser Systems; SPIE 3437-05 (1998); pages 1-11.
	L Daniel R. Neal et al.; Amplitude and phase beam characterization using a two-dimensional wavefront sensor; SPIE Vol. 2870, 0-8194-2267-3/96; pages 72-82.
	M Daniel R. Neal et al.; Use of beam parameters in optical component testing; 4451, pages 394-405.
	N D.R. Neal et al.; Wavefront sensors for optical diagnostics in fluid mechanics: application to heated flow, turbulence and droplet evaporation; SPIE Vol. 2005, 0-8194-1254-6/93; pages 194-203.
	O Lindlein et al.; Algorithm for expanding the dynamic range of a Shack-Hartmann sensor by using a spatial light modulator array; Optical Engineering, Vol. 40 No. 5 May 2001; pages 837-840.
	P Suzuki et al.; Error analysis of a Shack-Hartmann wavefront sensor; SPIE Vol. 2443, 0-8194-1792-0/95; pages 798-805.
	Q Platt et al.; History and Principles of Shack-Hartmann Wavefront Sensing; Journal of Refractive Surgery, Volume 17, September/October 2001; pages S573-S577.
	R Lindlein, et al.; Experimental results for expanding the dynamic range of a Shack-Hartmann sensor using astigmatic microlenses; Optical Engineering, Vol. 41 No. 2, February 2002; pages 529-533.
	S Lindlein et al.; Absolute sphericity measurement: a comparative study of the use of interferometry and a Shack-Hartmann sensor; Optics Letters / Vol. 23, No. 10 / May 15, 1998; pages 742-744.
/JS/	T Lindlein et al.; Dynamic range expansion of a Shack-Hartmann sensor by use of a modified unwrapping algorithm; Optics Letters / Vol. 23, No. 13 / July 1, 1998; pages 995-997.
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